An Atomic Force Microscopy error signal image of a faceted pore on the SrTiO$_3$ surface with an orientation near (111). The three-fold rotational symmetry perpendicular to the surface plane is evident in the facet pattern and the shape of the pore. The directions of the edges of the triangular facets are <110> and the pore, in the central part of the image, is 130 nm deep. The sample was polished and then thermally etched in air at 1400°C for 6 minutes. The black to white shading of the error image represents 0.4 nanoNewtons of difference between the actual probe signal and the set point value of the probe tip force.

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